Raman spectroscopic study of zircon to high pressure and temperature

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The four most intense Raman bands of zircon at wavenumbers >300 cm⁻¹ have been assigned to internal vibrations of the SiO₄ tetrahedra. Specific assignments include $v_3(SiO_4)$ (antisymmetric stretching) to the band at 1008 cm⁻¹, $v_1(SiO_4)$ (symmetric stretching) to the band at 974 cm⁻¹, $v_2(SiO_4)$ (symmetric bending) to the band at 439 cm⁻¹, and $v_4(SiO_4)$ (antisymmetric bending) or an external lattice mode to the band at 356 cm⁻¹ (Nasdala et al., 2003). The effect of pressure (*P*) on the frequency of these bands (and on the linewidth of $v_3(SiO_4)$) has previously been characterized at ~300 K for fully crystalline and radiation-damaged zircon (Knittle and Williams 1993, Nasdala et al. 2008). This has not been studied at elevated temperatures (*T*). Here, we determine the frequency and the linewidth of these Raman bands for fully crystalline synthetic zircon (ZrSiO₄ endmember composition) as functions of *P* and *T* to 6.6 GPa and 950 °C using a HORIBA LabRAM HR800 Raman microprobe (unpolarized spectra, backscattering geometry, gratings 1800 lines/mm, excitation by 488 nm line of Ar⁺ laser) and diamond-anvil cells or a Linkam TS1000 heating stage.

At 0.1 MPa, the v₂(SiO₄) band displays by far the largest increase in linewidth with *T* (from ~5 cm-1 at 22 °C to ~24 cm⁻¹ at 900 °C), while those for v₃(SiO₄) and v₁(SiO₄) are moderate (from ~2 cm⁻¹ at 22 °C to ~13 or 12 cm⁻¹ at 900 °C). The v₃(SiO₄) band shows the largest wavenumber decrease with *T* (~-0.038 cm⁻¹/K). The $\partial v/\partial T$ slopes of the other bands are ~-0.023 cm⁻¹/K for v₁(SiO₄), ~-0.017 cm⁻¹/K for v₂(SiO₄), and ~-0.019 cm⁻¹/K for the 356 cm⁻¹ band. The isothermal change in wavenumber with *P* is nearly constant for the studied Raman bands. At 23 °C, the obtained $\partial v/\partial P$ slope of the v₃(SiO₄) band to 6.6 GPa is 5.68 cm⁻¹/GPa, and 5.75 cm⁻¹/GPa to 2.5 GPa. This slope does not significantly change with *T*, as determined for the 700 and 600 °C isotherms ($\partial v/\partial P$ ~5.9 cm⁻¹/GPa) and along the 500 °C isotherm ($\partial v/\partial P$ ~6.1 cm⁻¹/GPa). At 23 °C, the $\partial v/\partial P$ slopes to 6.6 GPa of the other bands are 5.15 cm⁻¹/GPa for v₁(SiO₄), 1.45 cm⁻¹/GPa for v₂(SiO₄), and 4.55 cm⁻¹/GPa for the 356 cm⁻¹ band, and are not significantly different for isotherms at higher *T*. A general tendency of slight (often nonsignificant) decreases in the linewidths of the studied Raman bands with pressure was observed at 23 °C to 6.6 GPa, and along other isotherms to 700 °C to *P* of 1.3 GPa.

Because of its fairly large and temperature-independent shift with $P (\partial v/\partial P \sim 5.8 \text{ cm}^{-1}/\text{GPa})$, the frequency of the $v_3(\text{SiO}_4)$ (~1008 cm⁻¹) Raman band of fully crystalline synthetic zircon can be used as a pressure sensor for experiments using optical cells at high P and T. This is of particular advantage in situations where other phases cannot be used as pressure sensors because of phase transitions or high solubility. However, the actual sample temperature should be well known for accurate determination of P using this sensor because of the temperature sensitivity of the frequency, which is described by the equation $v(\text{cm}^{-1}) = 7.26*10^{-9}*T(^{\circ}\text{C})^{3} - 1.58*10^{-5}*T(^{\circ}\text{C})^{2} - 2.893*10^{-2}*T(^{\circ}\text{C}) + 1008.64$ ($22 \le T(^{\circ}\text{C}) \le 950$).

References:

Nasdala L. et al. (2003), Reviews in Mineralogy and Geochemistry, 53, 427-467.

Knittle E., Williams Q. (1993), American Mineralogist, 78, 245-252.

Nasdala L. et al. (2008), Physics and Chemistry of Minerals, 35, 597-602.